

## 10<sup>th</sup> International Conference of the European Society for Precision Engineering and Nanotechnology

Session 2: Nano & Micro Metrology

**Tuesday 1<sup>st</sup> June 2010, 11:30-13:15**

*Chairmen: Dr H. Bosse, PTB, DE & Dr H. Haitjema, Mitutoyo Research Centre, NL*

<b>O2.1 (Keynote)</b>	<b>Absolute Distance Measurements Using the Frequency Comb of a Femtosecond Pulse Laser</b> Seung-Woo Kim <i>Korea Advanced Institute of Science and Technology (KAIST), Korea</i>
<b>O2.2</b>	<b>Design and Preliminary Evaluation of a New Feedback-controlled Micro-tribometer</b> Derek Chetwynd <i>University of Warwick, UK</i>
<b>O2.3</b>	<b>A quantitative 193 nm DUV microscope</b> Dr Zhi Li <i>Physikalisch-Technische Bundesanstalt, DE</i>
<b>O2.4</b>	<b>A Single-mask Thermal Displacement Sensor in MEMS</b> Richard Hogervorst <i>DEMCON Advanced Mechatronics, NL</i>
<b>O2.5</b>	<b>Matching of Micro Gears via Dimensional Metrology and Functional Testing</b> Benjamin Viering <i>wbk Institute of Production Science, Karlsruhe Institute of Technology (KIT), DE</i>